Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
09/941,748	TAKEO ET AL.
Examiner	Art Unit
Craig W. Kronenthal	2623

	SEAR	CHED	
Class	Subclass	Date	Examiner
382	128	9/8/2005	ск
378	207	9/8/2005	СК
324	300	9/8/2005	ск
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
382	128	9/14/2005	ск	
378	207	9/14/2005	ск	
382	132	9/14/2015	olc	

SEARCH N	NOTES CH STRATEGY)
	DATE	EXMR
See attached East search	9/8/2005	ск
See attached IEEE search	8/24/2005	ск